

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/520,424	KOBAYASHI ET AL		
Examiner	Art Unit		
Michael A. Friedhofer	2832		

SEARCHED				
	SEAR	CHED		
Class	Subclass	Date	Examiner	
200	5a,511, 512,516, 517,406	12/21/2005	MAF	
341	22	12/21/2005	MAF	
345	168	12/21/2005	MAF	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARCH	STRATEGY	)
	DATE	EXMR
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